

result with a reference value to make a determination as to whether or not the result is good. However, in the conventional example described above, beside the image processing apparatus, an auto-focusing unit, a microscope, and electron beams are required, whereby the examination is conducted for each one of the through holes, or with an expanded image that is expanded at a high level of magnification.

IN THE CLAIMS

Please amend the claims in accordance with the following rewritten claims in clean form. Applicants include herewith an Attachment for Claim Amendments showing a marked up version of each amended claim.

Claim 1. (AMENDED) A through hole examination method comprising:

irradiating light from one side of a work piece having a through hole; and

detecting passing light by imaging the passing light from another side of the work piece by a sensor camera having a plurality of imaging elements,

wherein the examination is conducted by imaging with an imaging focal point of the sensor camera being shifted with respect to a surface of the work piece.

Claim 2. (AMENDED) A through hole examination method comprising:

irradiating light from one side of a work piece having a plurality of through holes;

imaging and detecting passing light from another side of the work piece by a sensor camera having a plurality of imaging elements,